

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>10/017,855</u>	Prepared by <u>BRS</u>	Tracking Number <u>05988030</u>	
Examiner-GAU <u>Maldonado, J - 2823</u>	Date <u>8/31/04</u>	Week Date <u>7/26/04</u>	
	No. of queries <u>1</u>	<u>FW(E)</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<u>PTO-1449</u>
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION		
a. Page Missing	<p>MESSAGE <u>PTO-1449: Please ^{either} initial or strike through entries on PTO-1449 form dated 03-29-2002. (Copy attached for reference)</u></p>	
b. Text Continuity		
c. Holes through Data		
d. Other Missing Text		
e. Illegible Text		
f. Duplicate Text		
g. Brief Description		
h. Sequence Listing		
i. Appendix		
j. Amendments		
k. Other		
CLAIMS		
a. Claim(s) Missing		<p><u>Thank You</u> initials <u>BRS</u></p> <p>RESPONSE</p>
b. Improper Dependency		
c. Duplicate Numbers		
d. Incorrect Numbering		
e. Index Disagrees		
f. Punctuation		
g. Amendments		
h. Bracketing		
i. Missing Text		
j. Duplicate Text		
k. Other		
initials		

Form PTO-1449
(MODIFIED)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

39153/441 (G0406)

10/017,855

APPLICANT

INFORMATION DISCLOSURE CITATION

Philip A. Fisher et al.

MAR 29 2002

FILING DATE

GROUP ART UNIT

(Use several sheets if necessary)

12/14/2001

To be determined

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A1	09/819,342		Shields et al.			03/28/01
	A2	09/819,343		Gabriel et al.			03/28/01
	A3	09/819,344		Okoroanyanwu et al.			03/28/01
	A4	09/819,552		Gabriel et al.			03/28/01
	A5	09/819,692		Okoroanyanwu et al.			03/28/01
	A6	09/820,143		Okoroanyanwu et al.			03/28/01
	A7	6,107,172	08/22/00	Yang et al.	438	585	
	A8	6,103,457	08/15/00	Gabriel	430	318	
	A9	5,965,461	10/12/99	Yang et al.	438	717	
	A10	5,003,178	03/26/91	Livesay	250	492.300	

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

A11	Livesay, W. R., "Large-area electron-beam source," Journal of Vacuum Science & Technology B. Vol. 11, No. 6, Nov./Dec. 1993, pp. 2304-2308. American Vacuum Society
A12	Yank, J. J. et al., "Electron Beam Processing for Spin-on Polymers and its Applications to Back-End-of-Line (BEOL) Integration," Materials Research Society Symposium Proceedings, Vol. 511, 1998, pp. 49-55. Materials Research Society
A13	Ross et al., "Plasma Etch Characteristics of Electron Beam Processed Photoresist," The Society of Photo-Optical Instrumentation Engineers, Vol. 2438, 1995, pp. 803-816. SPIE- The International Society for Optical Engineering
A14	Grün, Von A.E., "Lumineszenz-photometrische Messungen der Energieabsorption im Strahlungsfeld von Elektronenquellen Eindimensionaler Fall in Luft," Zeitschrift für Naturforschung, Vol. 12a, 1957, pp. 89-95. Publisher: Zeitschrift für Naturforschung; full English Translation attached (11 pgs.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next communication to applicant.